

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 248430US6		SERIAL NO. 10/768,088	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Ken IIZUKA					
		FILING DATE February 2, 2004		GROUP 2624			
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	2002/90109	7/11/02	WENDT			
	AB	2003/39405	2/27/03	OOSAWA			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	AO	JP 10-124667	5/15/98	JAPAN (w/ English Abstract)	YES	NO	X
	AP	JP 2000-268178	9/29/00	JAPAN (w/ English Abstract)			X
	AQ	JP 2003-153082	5/23/03	JAPAN (w/ English Abstract)			X
	AR	JP 3254622	11/30/01	JAPAN (w/ English Abstract)			X
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW	Hiroshi Sasaki, Koji Kobayashi, Takafumi Aoki, Masayuki Kawamata, Tatsuo Higuchi, "The Measurement of Rotation Angle of the Image by the Rotation Invariant Phase-Limited Correlation," Institute of Image Information and Television Engineers technical report, Japan, Institute of Image Information and Television Engineers, September 14, 1998, Vol. 22, No. 45, p. 55-60					
	AX	Nobuhumi Sasaki, Kenji Takita, Takafumi Aoki, Tatsuo Higuchi, Koji Kobayashi, "High Accuracy Registration based on the Phase-limited Correlation Method," Institute of Electronics, Information and Communication Engineers Technical Study Reports [Imaging Engineering], Japan, Institute of Electronics, Information and Communication Engineers, April 11, 2002, Vol. 102, No. 11, p. 49-54, IE2002-9					
	AY	Yagi, "Image Processing and Lighting 4, Correlation of the Fluctuation of Lighting Part (2)," Image Information, Japan Industry Development Organization, July 1, 2000, Vol. 32, No. 13, p. 48-53, 92					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				Date Considered			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							